

# INTERNATIONAL STANDARD

## NORME INTERNATIONALE

**Integrated circuits – Measurement of electromagnetic emissions –  
Part 8: Measurement of radiated emissions – IC stripline method**

**Circuits intégrés – Mesure des émissions électromagnétiques –  
Partie 8: Mesure des émissions rayonnées – Méthode de la ligne TEM à plaques  
(stripline) pour CI**



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## INTERNATIONAL ELECTROTECHNICAL COMMISSION

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**INTEGRATED CIRCUITS –  
MEASUREMENT OF ELECTROMAGNETIC EMISSIONS –**
**Part 8: Measurement of radiated emissions –  
IC stripline method**

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Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

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This part of IEC 61967 is to be read in conjunction with IEC 61967-1.

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